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| Notice of References Cited | Application/Control No. 10/598,357 | | Applicant(s)/Patent Under Reexamination LESARTRE ET AL. | |
| | Examiner DIMPLE N. BODAWALA | | Art Unit 1791 | Page 1 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------------|----------------|
| * | A | US-3,368,245 A | 02-1968 | WITKOWSKI HENRY J | 425/215 |
| * | B | US-3,894,710 A | 07-1975 | Sarofeen, George M. J. | 249/117 |
| * | C | US-4,252,294 A | 02-1981 | Uchio, Shunji | 249/105 |
| * | D | US-4,693,446 A | 09-1987 | Orlosky, Henry | 249/53R |
| * | E | US-5,139,724 A | 08-1992 | Hofstetter et al. | 264/101 |
| * | F | US-5,523,045 A | 06-1996 | Kudert et al. | 264/513 |
| * | G | US-5,656,210 A | 08-1997 | Hill et al. | 264/2.6 |
| * | H | US-6,416,689 B1 | 07-2002 | Keita et al. | 264/1.1 |
| * | I | US-2002/0163095 A1 | 11-2002 | Andino et al. | 264/2.2 |
| * | J | US-2003/0122281 A1 | 07-2003 | Osawa et al. | 264/328.12 |
| * | K | US-2003/0173692 A1 | 09-2003 | Su et al. | 264/2.5 |
| * | L | US-6,843,940 B2 | 01-2005 | Reed et al. | 264/2.2 |
| * | M | US-2005/0001140 A1 | 01-2005 | Su et al. | 249/120 |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | WO03/084728 A1 | 10-2003 | DERWENT | KADOTA et al. | B29C 45/00 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | I | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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|-----------------------------------|---------------------------------------|--|---|-------------|
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| | Examiner DIMPLE N. BODAWALA | | Art Unit 1791 | Page 2 of 2 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|---------------|----------------|
| * | A | US-2005/0200033 A1 | 09-2005 | Kadota et al. | 264/001.31 |
| | B | US- | | | |
| | C | US- | | | |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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